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(Based on PTO 04-07 version)

Substitute for form 1449/PTO				Complete If Known	
				Application Number	10/518,284-Conf. #3519
				Filing Date	September 2, 2005
				First Named Inventor	Peter Hoghoj
				Art Unit	2882
				Examiner Name	C. C. G. Kao, J. Yun
Sheet	1	of	2	Attorney Docket Number	XENOCS 3.3-002

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
AA*	US-5,999,262-A	12-07-1999	Dohschal et al.		
AB*	US-6,317,483-B1	11-13-2001	Chen		
AC*	US-5,799,050-A	08-25-1998	Gutman		
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AG*	US-4,562,583-A	12-31-1985	Hoover et al.		
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FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear
BA	EP-0115892		08-15-1984	Philips Nv	✓
BB	WO-02/103710-A2		12-27-2002	X-Ray Optical Systems, Inc.	✓
BC	GB-2217036-A		10-18-1989	Rosser	✓
BD	WO-108162	01	02-01-2001	Univ California	✓

AE 6-19-08

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. *CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.58(e)(2)(B)) because that application was filed after June 30, 2003 or is available in the IFW. ¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
CA	NAUDON et al., "New Apparatus for Grazing Reflectometry in the Angle-Resolved Dispersive Mode", J. Appl. Cryst., Vol. 22, Part 5, pp. 460-464, October 1, 1989.				
CB	M.P. Ulmer, Production and performance of multilayer coated conic sections, Jul 2001, SPIE, Vol. 4496, page 127-133.				
CC	M.P. Ulmer, The Fabrication of Wolter I multilayer coated optics via electroforming: an update, Jul 1999, SPIE, Vol. 3773, page 113-121.				
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CE	Romaine et al., Multilayer Optics for Hard X-ray Astronomy, SPIE, Vol. 4138, Nov. 2000, page 120-125.				
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CG	G.E. ICE, "Microbeam Forming Methods for Synchrotron Radiation," © 1997				

Examiner Signature 772965	<i>Juric Yun</i>	Date Considered	6-19-07
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